

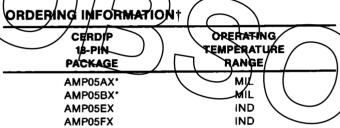
Fast Settling JFET Instrumentation Amplifier

AMP-05

FEATURES

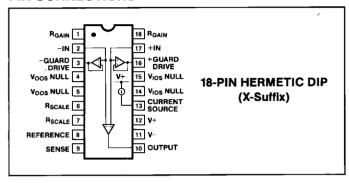
- Settling-Time to 12-Bit Accuracy, G ≤ 2000 15μs Max
- Overload Recovery Time, G = 100015μs
- 14-Bit Gain Linearity at G ≤ 1000
- On-Board Dual Guard Drivers
- On-Board 100μA Precision Current Source
- Temperature Stable CMR
 - 105dB Min Over -55°C to +125°C
 - High Stew-Rate with 500pF Load5V/μs Min
- Input Overload Protected to ±30V Differential

Available in Die Form



- For devices processed in total compliance to MIL-STD-883, add /883 after part number. Consult factory for 883 data sheet.
- † Burn-in is available on commercial and industrial temperature range parts in CerDIP, plastic DIP, and TO-can packages.

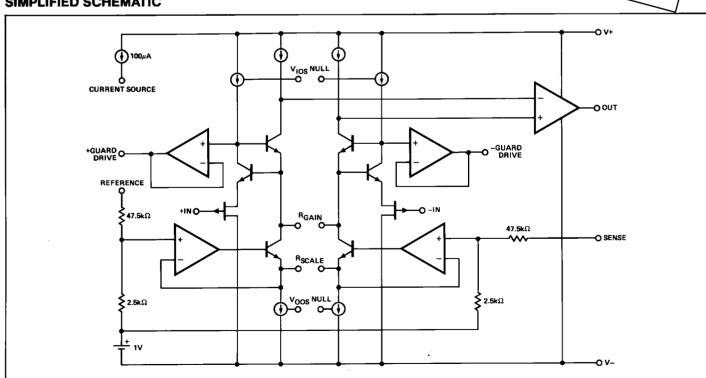
PIN CONNECTIONS



GENERAL DESCRIPTION

The AMP-05 is a fast JFET instrumentation amplifier designed for high-speed analog signal-processing and analog-multiplexed data acquisition systems. Settling-time to 12-bits is 15 µs maximum, with better than 14-bit linearity at all gains up to 1000. Two functions are added to the instrumentation amplifier that reduce external component count in many applications. Onboard dual guard drivers maintain good settling-time and common-mode rejection performance when shielded cable connects the input signal to the AMP-05. A precision 100 µA current source is also provided for transducer excitation, powering a low-current voltage reference and other functions.

SIMPLIFIED SCHEMATIC



The AMP-05 employs a current-feedback technique which provides a high and stable common-mode rejection, 105dB minimum over the military temperature range. JFET inputs reduce bias current to 50pA maximum at 25°C and only 20nA maximum at 125°C; low bias current reduces errors due to signal-source resistance. Internal input protection allows a 30V differential overload at all gain settings. The AMP-05 recovers rapidly when an input overload is removed. Recovery time is typically 15 μ s following a 1000:1 overload, voltage gain set to 1000. AMP-05 voltage gain is set by the ratio of two external resistors over the range 0.1 to 2000 and a low gain temperature-coefficient of 20ppm/°C maximum is achievable in the range 1 to 1000.

The AMP-05's outputs can all drive large capacitive loads without oscillation. The amplifier output is guaranteed stable with loads up to 2,000pF and the guard drivers can tolerate up to 10,000pE without oscillation.

Sense and reference pins complete the output feedback-loop and provide an output ground reference, respectively. The reference pin may be used for zeroing system offsets, where auto-zero hardware is employed. Resistance in series with the reference terminal does not degrade common mode rejection on PMI's AMP-05, which is a significant problem with instrumentation amplifiers employing the three op amp donfiguration.

For applications requiring very low input offset voltage and low offset drift, or higher output drive capability, refer to the AMP-01-data sheet.

Supply Voltage			±18V
Common-Mode Input Vo	oltage	Supp	ly Voltage
Differential Input Voltage	e <u>.</u>		±30V
(Inputs must not exceed Output Short-Circuit Dur			Indefinite
Storage Temperature R			
Operating Temperature			,
AMP-05A, B		–55°C	to +125°C
AMP-05E, F			
Lead Temperature (Sok			
Junction Temperature (
PACKAGE TYPE	⊖ _{jA} (Note 2)	e _{jc}	UNITS
18-Pin Hermetic DIP (X)	74	7	°C/W

NOTES:

- 1. Absolute ratings apply to both DICE and packaged parts, unless otherwise noted.
- Θ_{jA} is specified for worst case mounting conditions, i.e., Θ_{jA} is specified for device in socket for CerDIP package.

ELECTRICAL CHARACTERISTICS at $V_S=\pm 15V$, $R_S=5k\Omega$, $R_L=2k\Omega$, $T_A=25^{\circ}C$, unless otherwise noted

							, ,	,	_	
			F	AMP-05A/E			AMP-05B/F		T L	
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	DNHTS	
GAIN										
Gain Range	G _R		0.1	_	2000	0.1	_	2000		
Gain Equation Accuracy		$G = 20 \times R_S/R_G$ $G = 1 \text{ to } 1000$	_	0.25	0.5	_	0.4	1.0	%	
		G = 1	_	0.001	_	_	0.001	_		
Gain Nonlinearity		G = 10	_	0.002	_	_	0.002	_	0/	
		G = 100	_	0.007	_	_	0.007	_	%	
	G_{NL}	G = 1000	_	0.020	_	_	0.020			
		$R_L = 10k\Omega$								
		G = 100	_	0.004	_	_	0.004	_	%	
		G = 1000	_	0.004	-	_	0.004	_		
Gain Temperature		G = 1 to 100	_	1.7	10	_	1.7	10		
Coefficient	G _{TC}	G = 1000	_	8	20	_	8	20	ppm/°C	
Coefficient		(Notes 1, 2)								
OUTPUT RATING										
Output Voltage		$R_L = 1k\Omega$	±11	±12		±11	±12	_	v	
Swing	V _{OUT}	Over Temperature	±10.5	±12	-	±10.5	±12	_	V	
Short Circuit Current	I _{sc}	Output Shorted to Ground	±20	±35	_	±20	±35	_	mA	
Capacitive Load Stability		Full Gain Range No Oscillations	2	10	_	2	10	_	nF	

NOTES:

- 1. Gain tempco does not include the effects of gain and scale resistor tempco match.
- 2. Guaranteed but not 100% production tested.

 $\textbf{ELECTRICAL CHARACTERISTICS} \text{ at } V_S = \pm 15 \text{V}, \ R_S = 5 \text{k}\Omega, \ R_L = 2 \text{k}\Omega, \ T_A = 25 ^{\circ}\text{C}, \ \text{unless otherwise noted.} \ (\text{Continued})$

DADAMETER	0/4504			MP-05A			MP-05B	/F	
PARAMETER	SYMBOL	CONDITIONS	MIN_	TYP	MAX	MIN	TYP	MAX	רואט
INPUT									
Input Bias		T _A ≤ 25°C	_	20	50	_	30	100	р
Current	l _B	T _A = 85°C (E/F Grades)	_	0.5	4	_	1	8	n
		$T_A = 125^{\circ}C (A/B \text{ Grades})$	_	7	20	_	12	30	n
Input Offset	<u> </u>	T _A ≤ 25°C	_	5	25		10	50	p,
Current	los	T _A = 85°C (E/F Grades)	–	0.05	0.5		0.1	1	n,
		T _A = 125°C (A/B Grades)		1	5		2	10	n/
Input Resistance	R _{IN}			1012	_	_	1012	_	9
Input Capacitance	C _{IN}			8	_	-	8	_	p
Input Voltage	IVR	T _A = 25°C	±11	±11.5	_	±11	±11.5	_	
Range		Over Temperature	±10	±11		±10	±11		•
)		$V_{CM} = \pm 11V$							
11//		G = 1000	110	115	_	100	110	_	
/ / / ^	\mathcal{O})	G = 100	105	115	_	95	110	_	di
Common Mode		G(= 10)	100	110	_	90	100	_	
	OMR	G	90	98	_	80	90	_	
Rejection	\cup) \vdash	V _{CM} = ±10V, Over Temperature	\ /7						
	\mathcal{I}	G = 1000) /105/	110		95	105	_	
		G-160 / (/	/ / 100/	110	/	7 ,80	105	_	dl
	`	G=10 \ \	/ / 9 \$	105	/	\int_{85}	95	_	-
		G = 1	/ a fs	95 /		75	85		
OFFSET VOLTAGE			-		$\overline{}$	+	-	/ _ `	$\overline{}$
				\rightarrow $+$	-	-+			\searrow
nput Offset		$V_{CM} = 0V$	_	~ [- /	1 1		_
Voltage	V _{IOS}	T _A = 25°C	_	0.3		+	/ 0.5 /	120	
<u></u>		Over Temperature	_	0.8	2.0	t_/	1.0	4.0	7
put Offset	TCVIOS		_	5	10	7			
Voltage Drift					10	_	7	20] ^{μ۷/°C}
Output Offset	V	T _A = 25°C	_	3	15		5	25	
Voltage	V _{oos}	Over Temperature		9	25	_	11	40	m۷
Output Offset Voltage Drift	TCV _{oos}		_	50	100		70	150	μV/°C
		G = 1000	115	120		110	115		
		G = 100	110	118		105	110	_	
		G = 10	95	105	_	90	100		dB
Offset Referred to		G = 1	75	85	_	90 70	80	_	
Input vs. Positive	+PSR	Over Temperature							
Supply		G = 1000	110	440		405			
V+ = +5V to +15V			110	116	_	105	110	_	
		G = 100	105	114	_	100	105	_	d∃
		G = 10	90	102	_	85	98	_	
		^ 1	75	84	_	70	80		
-		G = 1 ·		_					
		G = 1000	110	118	_	105	110	_	
		G = 1000 G = 100	110 95	104	<u>-</u>	90	110 98	_	٦ ٠
		G = 1000	110					_ _ _	dB
offset Referred to		G = 1000 G = 100	110 95	104	-	90	98	_	dE
offset Referred to Input vs. Negative Supply	-PSR	G = 1000 G = 100 G = 10	110 95 75	104 84	<u>-</u>	90 70	98 80	_ _	dB
Input vs. Negative Supply	-PSR	G = 1000 G = 100 G = 10 G = 1	110 95 75	104 84	<u>-</u>	90 70	98 80	_ _	dB
Input vs. Negative	-PSR	G = 1000 G = 100 G = 10 G = 1	110 95 75 55	104 84 64	<u>-</u>	90 70 50	98 80 60	_ _	
Input vs. Negative Supply	-PSR	G = 1000 G = 100 G = 10 G = 1 Over Temperature G = 1000	110 95 75 55	104 84 64	<u>-</u>	90 70 50	98 80 60	_ _	dB

			A	MP-05A	/E	A	MP-05B	/F	
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	UNITS
Input Offset Voltage Trim Range		$V_{S} = \pm 4.5V \text{ to } \pm 18V$	±2.5	±5	_	±2.5	±5	_	m\
Output Offset Voltage Trim Range		$V_S = \pm 4.5 V$ to $\pm 18 V$	±25	±40	_	±25	±40	_	m۱
SENSE INPUT									
Input Resistance	R _{IN}	,	40	50 ·	60	40	50	60	kſ
Input Current	I _{IN}	Referenced to V-		280	_	_	280		μF
REFERENCE INPUT									
Input Resistance	R _{IN}		40	50	60	40	50	60	k£
Input Current	l ^{IN}	Referenced to V-	_	280	_	_	280	· _	μF
Voltage Range		<u> </u>	-10.5	_	+20	-10.5	_	+20	V
Gain o Output	1		_	1	_	_	1	_	V/\
NOISE									
Voltage Density RTI	en	Y _O = 1kNdz G ≥ 100 G = 10 G = 1		16 36 350	- - -/		16 38 7 350	_ _ _ _	nV/√Hz
Noise Current Density	in	f _O = 1kHz) 	10			لهر		∱A/√Hz
Input Noise Voltage	e _{np-p}	Measured at G = 1000, 0.1Hz to 10Hz Bandwidth		4	J/L	7	/4 /	/ /	μV_{p-1}
Output Noise Voltage	e _{np-p}	Measured at G = 0, 0.1Hz to 10Hz Bandwidth	_	7	_	\supset	7	1	$\int \mu V_{p-1}$
Input Noise Current	i _{np-p}	0.1Hz to 10Hz Bandwidth	_	0.12	_	_	0.12		pA_{p-1}
DYNAMIC RESPONSE									
Small Signal Bandwidth (~3dB)	BW	G = 1 G ≥ 10	_ _	3 120		_	3 120	_	MH2 kH2
Slew Rate	SR	C _L = 500pF G ≥ 10 Over Temperature	5 3.5	7.5 5.5	-	5 3.5	7.5 5.5	- -	V/ μ:
Settling Time	t _S	1 ≤ G ≤ 2000 -10V to +10V Step (Note 1) to 0.1% to 0.05% to 0.025%	_ _ _	5 7 10	7 10 15	_ _ _	5 7 10	7 10 15	μ
Overload Recovery Time	t _{rec}	G = 1000 V _{IN} = 10V to 10mV	_	15	_	_	15	_	μ

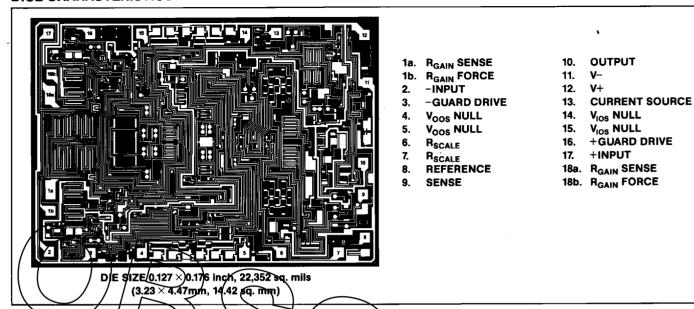
NOTE:

^{1.} Guaranteed but not 100% production tested.

 $\textbf{ELECTRICAL CHARACTERISTICS} \text{ at } V_S = \pm 15 \text{V, } R_S = 5 \text{k}\Omega, \ R_L = 2 \text{k}\Omega, \ T_A = 25^{\circ}\text{C, unless otherwise noted. (Continued)}$

			AN	AMP-05A/E		AMP-05B/F				
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	UNITS	
GUARD DRIVERS							•			
Output Voltage	v _o	Volts above respective input over temperature.	0.5	1.2	2.0	0.5	1.2	2.0	V	
Peak Output Current			8	15		8	15	_	mA	
Slew Rate	SR	C _L = 1000pF	-	16	_		16	_	´V/μs	
Capacitive Load Stability		No Oscillations (Note 1)	10	100	_	10	100	_	nF	
CURRENT SOURCE										
Current Output	I _{OUT}	Over Full Compliance Range	90	100	120	90	100	120	μА	
Output Compliance		V _{OC} Volts Below V+ (Irrespective of V-)	4	_	30	4	_	30	V	
Output Impedance	Rout	Over Full Compliance Range (Note 1)	1	3	_	1	3	_	GΩ	
Temperature Coefficient			_	100	_	-	100	-	ppm/°C	
Power Supply Rejection	$\mathcal{I}(\mathcal{C})$		17	150	_	_	150	_	nA/V	
POWER SUPPLY -25°C	= T _A ≤ +85°C	or EVF Grades, -55° C \leq T _A \leq +125	°C for A/B/Grade	S						
Supply Voltage Range	V _S		4.5	_	± 8	145	7	→ ±18	V	
Quiescent Current	I _Q			7.0	9:0	J - ,	7.5	J /10.0	A	
NOTE: 1. Guaranteed but not	100% productio	on tested.][7				

DICE CHARACTERISTICS



WAFER TEST LIMITS at $V_S = \pm 15V$, $R_S = 5k\Omega$, $R_L = 2k\Omega$, $T_A = 25^{\circ}$ C, unless otherwise noted.

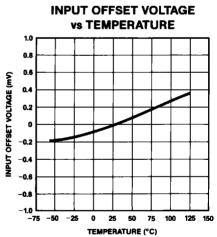
	_			
PARAMETER	SYMBOL	CONDITIONS	AMP-05GBC	UNITS
Input Offset Voltage	V _{ios}	V _{CM} = 0	2.0	mV MAX
Output Offset Voltage	V _{oos}		25	/ hv MAX
Offset Referred to Input vs. Positive Supply	PSR	V+ = +5V to +15V G = 1000 G = 100 G = 10 G = 1	110 105 90 70	dB MIN
Offset Referred to Input vs. Negative Supply	PSR	V- = -5V to -15V G = 1000 G = 100 G = 10 G = 1	105 90 70 50	dB MIN
Input Bias Current	l _B		100	pA MAX
Input Offset Current	los		50	pA MAX
Input Voltage Range	IVR	Guaranteed by CMR Tests	±11	V MIN
Common-Mode Rejection	CMR	$V_{CM} = \pm 11V$ $G = 1000$ $G = 100$ $G = 10$ $G = 1$	100 95 90 80	dB MIN
Gain Equation Accuracy		$G = 20 \times R_{S}/R_{G}$ $G = 1 \text{ to } 100$	1.0	% MAX
Output Voltage Swing	V _{OUT}	$R_L = 1k\Omega$	±11	V MIN
Output-Current Limit		Output-to-Ground Short	±20	mA MIN
Current Source	Гоит		90 120	μΑ MIN μΑ MAX
Quiescent Current	la		±10.0	mA MAX

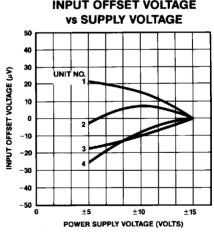
NOTE:

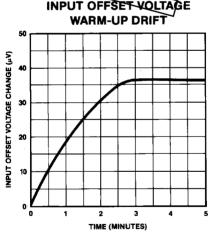
Electrical tests are performed at wafer probe to the limits shown. Due to variations in assembly methods and normal yield loss, yield after packaging is not guaranteed for standard product dice. Consult factory to negotiate specifications based on dice lot qualification through sample lot assembly and testing.

TYPICAL ELECTRICAL CHARACTERISTICS at $V_S=\pm 15V$, $R_S=5k\Omega$, $R_L=2k\Omega$, $T_A=25^{\circ}C$, unless otherwise noted.

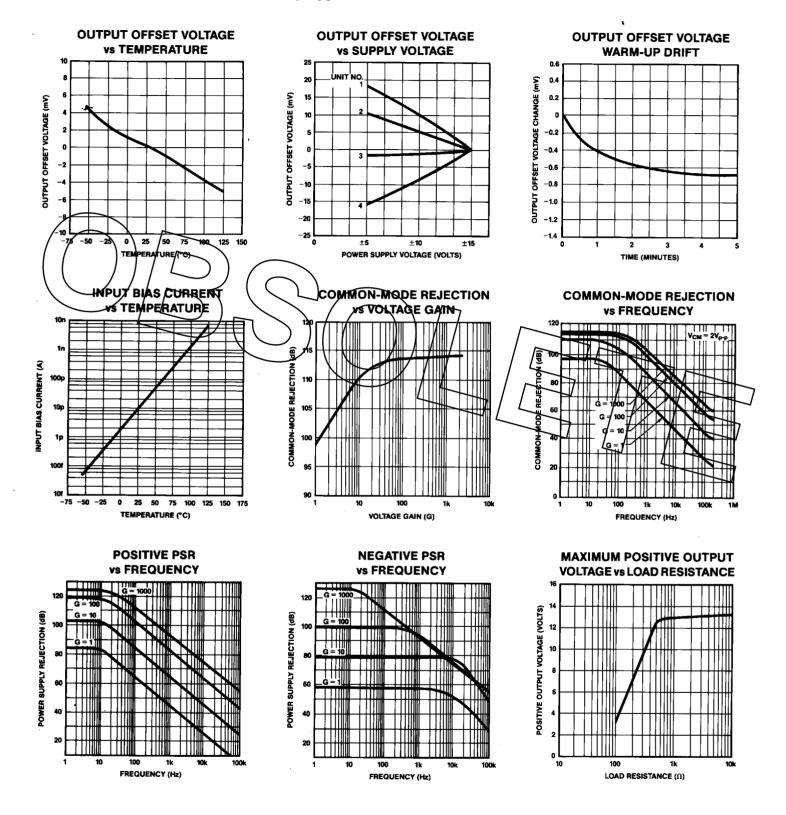
PARAMETER	SYMBOL	CONDITIONS	AMP-05GBC TYPICAL ,	UNITS
Input Offset Voltage Drift	TCV _{IOS}		7	μV/°C
Output Offset Voltage Drift	TCV _{oos}	R _G = ∞	70	μ У /°C
Nonlinearity		$G = 1000$ $R_L = 10k\Omega$	0.004	%
Voltage Noise Density	e _n ,	$G = 1000$ $f_O = 1 kHz$	16	nV/√ Hz
Current Noise Density	in	G = 1000 f _O = 1kHz	10	fA/√Hz
Veltage Noise	e _{np-p}	G = 1000 0.1Hz to 10Hz	4	μV _{p-p}
Current Noise	ing-p	G = 1000 0.1Hz to 10Hz	0.12	pA _{p-p}
Small-Signal Bandwidth (+3dB)	BW	G = 1000	120	kHz
Slew Rate) sk	G = 10	7.5	V/μs
Settling Time	ts	To 0.025% -10V to +10V Step 1 = G = 2000	10	με
Overload Recovery Time	t _{rec}	G = 1000 V _{IN} = 10V to 10mV	15	μ\$
TYPICAL PERFORM	ANCE CHARA	CTERISTICS		
INPUT OFFSET		INPUT OFFSET VOLTAGE vs SUPPLY VOLTAGE	INPUT OFFS	ET VOLTAGE



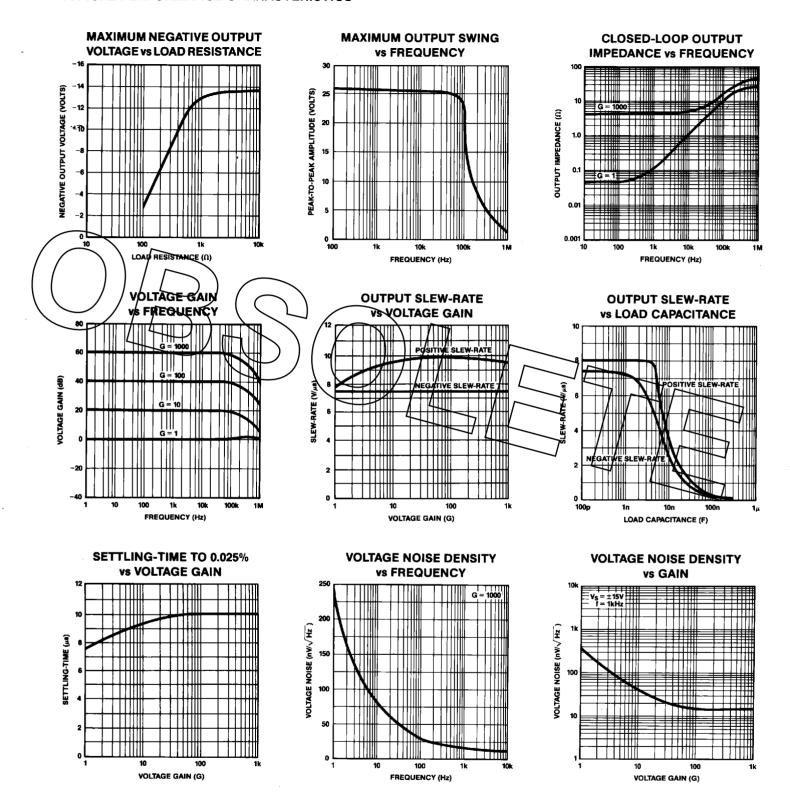




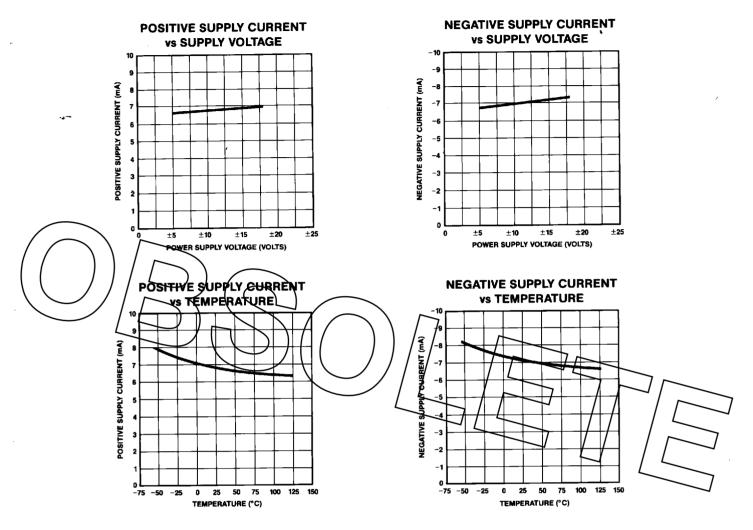
TYPICAL PERFORMANCE CHARACTERISTICS



TYPICAL PERFORMANCE CHARACTERISTICS



TYPICAL PERFORMANCE CHARACTERISTICS



APPLICATIONS INFORMATION

VOLTAGE GAIN

The AMP-05 uses two external resistors for setting voltage gain over the range 0.1 to 2000. The magnitudes of the scale resistor, R_{S} , and gain-set resistor, R_{G} , are related by the formula: $G=20\times R_{S}/R_{G}$, where G is the selected voltage gain. Figure 1 shows the amplifier connections. R_{G} can be selected using the graph in Figure 2.

Circuit performance is characterized using R_S = $5k\Omega$ operating on ± 15 volt supplies and driving a ± 10 volt output.

Metal-film or wirewound resistors are recommended for R_S and R_G . The absolute resistance values and temperature coefficients of resistance are not too important; only the ratiometric parameters are important for gain accuracy and stability.

FIGURE 1: Basic AMP-05 Connections For Gains 0.1 to 2000

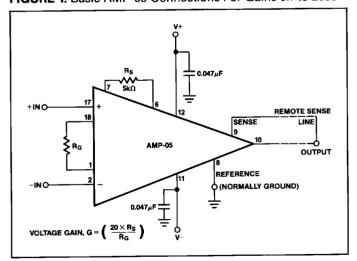
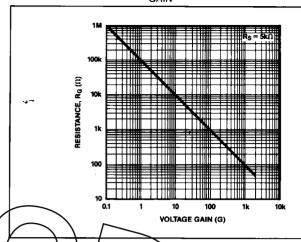


FIGURE 2: Selection of RGAIN



AC amplifiers require good gain stability with temperature and time, but DC performance is unimportant. Therefore, low cost metal-film types with TSs of 50 ppm/°C are usually adequate for Rs and RG. Realizing the full potential of the AMP-05's gain stability requires precision metal-film or wirewound resistors. Achieving a 25 ppm/°C max. gain temperature to 5 ppm/°C max.

Gain accuracy is determined by the ratio accuracy of R_S and R_S combined with the gain equation error of the AMP-05 (0.5% for A/E grades).

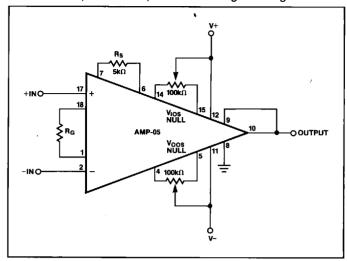
Note: The AMP-05 is inherently stable at all gains. However, like all amplifiers with a high gain-bandwidth product, instability can occur if layout precautions are not observed: (a) the amplifier should be decoupled close to the supply pins, and (b) the output must be kept well away from the inputs, the null pins, and R_{GAIN} .

The AMP-05 is capable of gain-bandwidth products in the hundreds of megahertz when operated at its highest gain settings. Under these conditions, even a few picofarads of stray feedback to the inputs can cause instability, and the situation is exacerbated if the input signal has a high source impedance. If instability does occur, the problem is easily eliminated by placing a small capacitor directly between the AMP-05's input pins, 2 and 17.

INPUT AND OUTPUT OFFSET VOLTAGES

Instrumentation amplifiers have independent offset voltages associated with the input and output stages. While the initial offsets may be adjusted to zero, temperature variations will cause shifts in offsets. Systems with auto-zero can correct for offset errors, so initial adjustment would be unnecessary. However, many high-gain applications do not have auto-zero. For these applications both offsets can be nulled. Nulling has minimal effect on TCV_{IOS} and TCV_{OOS} (refer to Figure 3 for connections).

FIGURE 3: Input and Output Offset Voltage Nulling



The input offset component is directly multiplied by the amplifier gain, whereas output offset is independent of gain. Theyefore, at low gain, output offset errors dominate, while at high gain, input offset errors dominate. Overall offset voltage, Vos., referred to the output (RTO) is calculated as follows:

The overall offset voltage drift, TCV_{OS}, referred to the output, is a combination of input and output drift specifications. Input offset voltage drift is multiplied by the amplifier gain, G, and summed with the output offset drift;

$$\mathsf{TCV}_{\mathsf{OS}}\left(\mathsf{RTO}\right) = \left(\mathsf{TCV}_{\mathsf{IOS}} \times \mathsf{G}\right) + \mathsf{TCV}_{\mathsf{OOS}} \ \ldots \ldots (2)$$

where TCV_{IOS} is the input offset voltage drift, and TCV_{OOS} is the output offset voltage drift specification. Frequently, the amplifier drift is referred back to the input (RTI) which is then equivalent to an input signal change;

$$TCV_{OS} (RTI) = TCV_{IOS} + \frac{TCV_{OOS}}{G} \(3)$$

For example, the maximum input-referred drift of an AMP-05EX set to G = 100 becomes:

$$TCV_{OS} (RTI) = 10\mu V/^{\circ}C + \frac{100\mu V/^{\circ}C}{100} = 11\mu V/^{\circ}C \text{ max.}$$

INPUT BIAS AND OFFSET CURRENTS

Input bias currents are additional error sources which can degrade the input signal. Bias currents flowing through the signal source resistance appear as an additional offset voltage. Equal source resistance on both inputs of an instrumentation amplifier will minimize offset changes due to bias current variations with signal voltage and temperature. However, the difference between the two bias currents, the input offset current, produces a nontrimmable error. The magnitude of the error is the offset current times the source resistance.

The AMP-05 has FET inputs which have negligible bias and offset currents at room temperature and consequently can accurately measure signals from high source impedances. However, like all FET devices, the bias current doubles approximately every 10°C increase in junction temperature and therefore bias and offset currents must be carefully considered when operating up to +125°C.

Note: If very high source impedances (\sim 1M Ω) are used and the AMP-05 is used at high gain, then it is recommended that a small capacitor is connected across the inputs to prevent instability.

A current path must always be provided between the differential inputs and analog ground to ensure correct amplifier operation. Floating inputs, such as thermocouples, should be grounded close to the signal source for best common-mode rejection.

OVERVOLTAGE PROTECTION

The AMP-05 features a unique internal protection circuit which permits differential input voltages of up to ± 30 V even when set for high gain operation. It should be noted however, that the output state during such an overload is not defined. Typically, at gains above 10, severe overloads ($\approx 1000\%$ overrange) will cause the output to sit at about +10V with a low-level oscillation apparent.

Additionally, gross overdriving will cause input currents of up to $100\mu A$ to flow in the lower of the two inputs. The increased input current should be borne in mind if interfacing to extremely delicate transducers.

OVERLOAD RECOVERY TIME

Following an input overload, an amplifier takes a finite time to recover, i.e. the amplifier's output has to return to the linear operating region after limiting at one or other supply. The AMP-05 is designed to recover rapidly from input overloads; typically recovery time is 15μ s following a 1000:1 overload; voltage gain set to 1000.

Rapid overload recovery is particularly important in a multiplexed data acquisition system using programmable gain. In this application, it is possible for the input to be switched to a high-level signal with gain set high, thus overloading the amplifier. To maintain system speed, it is vital for the amplifier to recover quickly once the overload is removed by reprogramming the gain.

COMMON-MODE REJECTION

Ideally, an instrumentation amplifier responds only to the difference between the two input signals and rejects common-mode voltages and noise. In practice, there is a small change in output voltage when both inputs experience the same common-mode voltage change; the ratio of these voltages is called the common-mode gain. Common-mode rejection (CMR) is the logarithm of the ratio of differential-mode gain to common-mode gain, expressed in dB. CMR specifications are normally measured with a full-range input voltage change and a specified source resistance unbalance.

The current-feedback design used in the AMP-05 inherently yields high common-mode rejection. Unlike resistive feedback designs typified by the three-op-amp IA, the CMR is not degraded by small resistances in series with the reference input. A slight, but trimmable, output offset voltage change results from resistance in series with the reference input.

The common-mode input voltage range, CMVR, for linear operation may be calculated from the formula:

$$CMVR = \frac{1}{2G} \left(\frac{VR}{2G} \right) \cdot \frac{(4)}{2G}$$

IVR is the data sheet specification for input voltage range; $V_{\rm QUT}$ is the maximum output signal; and G is the chosen voltage gain. For example, at 25°C, IVR is specified as ± 11 volts minimum with ± 15 volt supplies. Using a ± 10 volt maximum swing output and substituting the figures in (4) simplifies the formula to:

$$\text{CMVR} = \pm \left(11 - \frac{5}{G} \right) \quad \dots \qquad (5)$$

For all gains greater than or equal to 5, CMVR is ± 10 volt minimum; at gains below 5, CMVR is reduced.

GUARD DRIVERS

Dual guard drivers are included to restore bandwidth, settling-time, and high frequency common-mode rejection (CMR) when shielded cable is used at the input. The guard drivers can handle large capacitive loads and transient currents, but they are not intended for large DC loads. The DC path to ground should be $30k\Omega$ or greater; lower values can upset the AMP-05's internal biasing circuits.

Shielded cable is often employed to minimize capacitively coupled noise pickup along the signal path from source to amplifier. When coaxial cable connects a transducer to the amplifier's input, the cable's capacitance interacts with the transducer's source impedance to form a low-pass filter. This filter function reduces the amplifier's bandwidth and degrades settling-time and CMR. The AMP-05's differential guard drivers act as an AC "bootstrap" when attached to the coaxial shields. In bootstrapping, each driver follows its corresponding input, and the driver output signals are buffered to handle large capacitive loads. Each driver will typically slew at 16V/µs with a 1000pF load. Bootstrapping reduces the effective input capacitance, since no AC voltage appears between the shield and laner conductor.

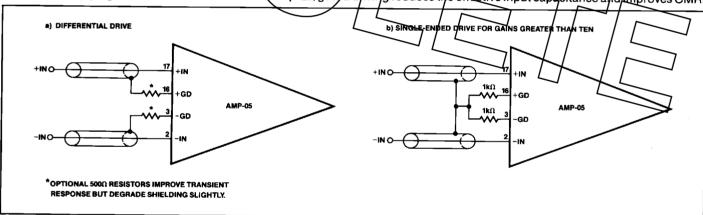
The AMP-05's gulard drivers can form either a differential or single-ended drive (refer to Figures 4(a) and b). In the single-ended arrangement, the two input cable shields are held at the

same potential, the common-mode voltage (Figure 4(b)). As such, the connection is also appropriate for one shielded twisted-pair cable. The single-ended arrangement maintains a high CMR even at high frequencies, but does not reduce high frequency gain degradation as it does not counteract differential-mode capacitance. Single-ended drive is acceptable for gains greater than ten using the circuit in Figure 4(b). However the differential connection, Figure 4(a), offers better overall performance because it effectively reduces both differential and common-mode capacitance. Reduction in these capacitances improves high-frequency CMR, settling-time, and gain.

It should be noted that all shield drive arrangements are potentially positive feedback configurations and under some conditions high frequency ringing may occur. If this proves troublesome, small resistors $(500\Omega\text{-}1k\Omega)$ in series with the cable shield outputs will improve transient response and settling-time but reduce the effectiveness of the cable shield, particularly at high frequency.

Short circuits from the cable drives to ground will not damage the AMP-05 but will result in malfunction of the AMP-05 until the short is removed. The package pins adjacent to the two inputs, $R_{\rm G}$ connections and guard drives, sit within 2 volts of the input signals. This feature reduces leakage currents to the input terminals and eliminates the need for guard-rings which are necessary on many FET input amplifiers.

FIGURE 4: Applying the Guard Drivers to shield the inputs guard driving reduces the effective input capacitance and improves CMR.



GROUNDING

The majority of instruments and data acquisition systems have separate grounds for analog and digital signals. Analog ground may also be divided into two or more grounds which will be tied together at one point, usually the analog power-supply ground. In addition, the digital and analog grounds may be joined, normally at the analog ground pin on the A-to-D converter. Following this basic grounding practice is essential for good circuit performance (Figure 5).

Mixing grounds causes interactions between digital circuits and the analog signals. Since the ground returns have finite resistance and inductance, hundreds of millivolts can be developed between the system ground and the data acquisition components. Using separate ground returns minimizes the current flow in the sensitive analog return path to the system ground point. Consequently, noisy ground currents from logic gates do not interact with the analog signals.

Inevitably, two or more circuits will be joined together with their grounds at differential potentials. In these situations, the differential input of an instrumentation amplifier, with its high CMR, can accurately transfer analog information from one circuit to another.

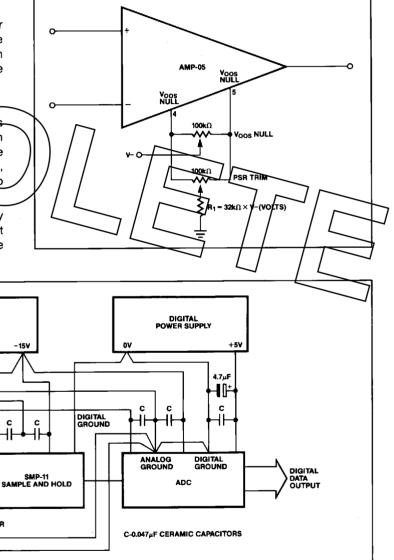
Using well stabilized, low-noise power supplies is always-recommended for precision analog circuits. However even with good supplies, there will be small changes in output voltage due to temperature variations and line voltage variations. In turn, these voltage changes will affect the amplifier output due to finite power-supply rejection (PSR).

The AMP-05's PSR can be maximized in critical applications by adding a trim potentiometer (see Figure 6). Positive PSR cannot be trimmed by external means but this is better than negative

PSR by as much as 20dB, and therefore trimming should not be necessary. Adjusting the negative PSR trim potentiometer also affects output offset voltage, V_{OOS} . Therefore in systems where offset correction is not employed, a V_{OOS} null potentiometer can be added if needed. In practice, the interaction between these two potentiometers is not a problem.

PSR/ V_{OOS} trimming procedure: 1) adjust both potentiometers to mid-position; 2) superimpose a low-frequency 1V peak-to-peak sinewave on the negative supply; 3) adjust PSR trim potentiometer for minimum output ripple; 4) remove AC signal from the power supply and null the AMP-05's output offset voltage using the V_{OOS} null potentiometer. Steps 1 and 4 are deleted when only PSR trimming is required.

FIGURE 6: Ádditional Trim Potentiometer Maximizes Negative PSR



ANALOG POWER SUPPLY

> HOLD CAPACITOR

OUTPUT REFERENCE

CURRENT SOURCE

The on-board $100\mu\text{A}$ current source is provided for transducer excitation, powering a low-current voltage reference diode, and other functions. The current source is referenced from the positive supply rail (V+), and provides a high voltage compliance from 4 to 30V below V+. The output should not be pulled below V-. Output resistance is typically $3G\Omega$. Simple positive and negative voltage references can be generated by adding two resistors and an inexpensive op amp (Figures 7(a) and (b)). Temperature stability can be improved by replacing R1 with a low-current zener or voltage reference diode such as the LM185. The output reference voltage can be increased beyond the zener voltage by adding resistor R3 to add gain around the OP-77.

If the current source is not used it may be left floating or connected to V-.

SENSE AND REFERENCE TERMINALS

The sense terminal completes the feedback path for the instrumentation amplifier output stage and is normally connected directly to the output. The output signal is specified with respect to the reference terminal, which is normally connected to analog ground.

If high output currents are expected and/or the load is situated some distance from the amplifier, voltage drops due to trace or wire resistance will cause errors. Under these conditions, the sense and reference terminals can be used to "remote sense" the load as shown in Figure 8. This method of connection puts the $I\times R$ drops inside the feedback loop and virtually eliminates the error. An unbalance in the lead resistances from the sense and reference pins does not degrade CMR, but will change the output offset voltage. For example, a large unbalance of 3Ω will change the output offset by only 1mV.

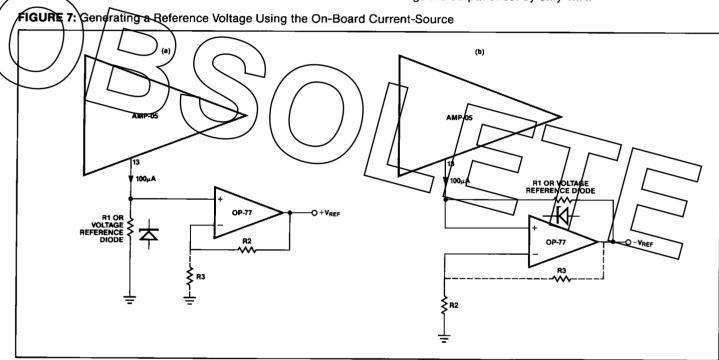


FIGURE 8: Remote Load Sensing

